## Notice of References Cited Application/Control No. 10/668,360 Applicant(s)/Patent Under Reexamination OHYAMA ET AL. Examiner BENJAMIN O. DULANEY Applicant(s)/Patent Under Reexamination OHYAMA ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,005,673 A	12-1999	Murai et al.	358/434
*	В	US-6,069,706 A	05-2000	Kajita et al.	358/1.15
*	C	US-2002/0051223 A1	05-2002	Izumi et al.	358/402
*	D	US-2002/0080250 A1	06-2002	OGAWA et al.	348/232
*	Е	US-2002/0122193 A1	09-2002	Shirasawa, Hisao	358/1.9
*	F	US-2002/0141380 A1	10-2002	Koguchi, Masatsugu	370/351
*	G	US-2002/0156923 A1	10-2002	Tanimoto, Yoshifumi	709/246
*	Ι	US-2002/0149784 A1	10-2002	Levin et al.	358/1.2
*	I	US-2002/0176105 A1	11-2002	Kawai et al.	358/1.9
*	J	US-2004/0233484 A1	11-2004	Seko et al.	358/523
*	K	US-7,221,465 B1	05-2007	Shimada, Hirokatsu	358/1.14
*	L	US-7,352,488 B2	04-2008	Ben-Chorin et al.	358/1.9
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Ø					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.